

## Projekty schválené k dofinancování ve 3. výzvě 2013 v rámci Evropského metrologického výzkumného programu

**EMRP**  
European Metrology Research Programme  
Programme of EURAMET



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### Seznam schválených projektů EMRP v roce 2013

ID kód	Název projektu	Akronym projektu	Číslo projektu	Hlavní řešitel, Název organizace  Český metrologický institut
7Ax13001	Metrology for drug delivery	MeDD	HLT07	Mgr. Jan Geršl, Ph.D.
7Ax13002	Metrology for radiotherapy using complex radiation fields	MetrExtRT	HLT09	Ing. Petr Kovář
7Ax13003	Metrology for molecular radiotherapy	MetroMRT	HLT11	Ing. Petr Kovář
7Ax13004	Traceable characterisation of nanostructured devices	TReND	NEW01	Mgr. Miroslav Valtr, Ph.D.
7Ax13005	Metrology for Raman spectroscopy	Raman	NEW02	Mgr. Petr Klapetek, Ph.D.
7Ax13006	Novel mathematical and statistical approaches to uncertainty evaluation	Uncertainty	NEW04	Mgr. Dominik Pražák, Ph.D.
7Ax13007	Traceable measurement of mechanical properties of nano-objects	MechProNo	NEW05	Mgr. Petr Klapetek, Ph.D.
7Ax13008	Traceability for computationally-intensive metrology	Tracim	NEW06	Doc. Ing. Vít Zelený, CSc.
7Ax13009	Microwave and terahertz metrology for homeland security	THzSecurity	NEW07	Ing. Martin Hudlička, Ph.D.
7Ax13010	Metrology of electrothermal coupling for new functional	Metco	NEW09	Mgr. Petr Klapetek, Ph.D.

	materials technology			
<b>7Ax13011</b>	High-accuracy optical clocks with trapped ions	Ionclock	SIB04	RNDr. Petr Balling, Ph.D.
<b>7Ax13012</b>	Developing a practical means of disseminating the new kilogram	Newkilo	SIB05	Mgr. Jaroslav Zůda
<b>7Ax13013</b>	Traceability of sub-nm length measurements	Subnano	SIB08	Mgr. Petr Křen
<b>7Ax13014</b>	Novel techniques for traceable temperature dissemination	NOTED	SIB10	Dr. Ing. Radek Strnad
<b>7Ax13015</b>	Single-photon sources for quantum technologies	SIQUTE	EXL02	Dott. Geiland Porrovecchio
<b>7Ax13016</b>	Metrology for optical and RF communication systems	MORSE	IND51	Ing. Martin Hudlička, Ph.D.
<b>7Ax13017</b>	Multidimensional reflectometry for industry	XD Reflect	IND52	Dr. Ing Marek Šmíd
<b>7Ax13018</b>	Novel electronic devices based on control of strain at the nanoscale	Nanostrain	IND54	Mgr. Miroslav Valtr, Ph.D.
<b>7Ax13019</b>	Metrology for processing materials with high natural radioactivity	Metronorm	IND57	Ing. Petr Kovář
<b>7Ax13020</b>	Metrology for movement and positioning in six degrees of freedom	6DoF	IND58	Mgr. Petr Klapetek, Ph.D.
<b>7Ax13021</b>	Improved EMC test methods in industrial environments	EMC	IND60	Ing. Marek Svoboda CSc.
<b>7Ax13022</b>	Metrology to enable high temperature erosion testing	Metrosion	IND61	Dr. Ing. Radek Strnad
<b>7Ax13023</b>	Traceable in-process dimensional measurement	TIM	IND62	Doc. Ing. Vít Zelený, CSc.
<b>7Ax13024</b>	Metrology for airborne molecular contamination in manufacturing environments	MetAMC	IND63	Ing. Jan Beránek

<b>7Ax13025</b>	Quantum resistance metrology based on graphene	GraphOhm	SIB51	Ing. Jan Kučera, Ph.D.
<b>7Ax13026</b>	Metrology for thermal protection materials	Thermo	SIB52	Dr. Ing. Radek Strnad
<b>7Ax13027</b>	Automated impedance metrology extending the quantum toolbox for electricity	AIMQuTE	SIB53	Ing. Jan Kučera, Ph.D.
<b>7Ax13028</b>	International timescales with optical clocks	ITOC	SIB55	Mgr. Jan Geršl, Ph.D.
<b>7Ax13029</b>	New primary standards and traceability for radiometry	NEWSTAR	SIB57	Dr. Ing. Marek Šmíd
<b>7Ax13030</b>	Angle metrology	Angles	SIB58	Ing. František Dvořáček
<b>7Ax13031</b>	A quantum standard for sampled electrical measurements	Q-WAVE	SIB59	Mgr. Martin Šíra
<b>7Ax13032</b>	Crystalline surfaces, self assembled structures, and nano-origami as length standards in (nano)metrology	CRYSTAL	SIB61	Mgr. Miroslav Valtr, Ph.D.
<b>7Ax13033</b>	Metrology for new electrical measurement quantities in high-frequency circuits	HFCircuits	SIB62	Ing. Martin Hudlíčka, Ph.D.
<b>7Ax13034</b>	Force traceability within the meganewton range	Force	SIB63	Ing. Petr Kašpar
<b>7Ax13035</b>	Metrology for moisture in materials	METefnet	SIB64	Dr. Ing. Radek Strnad
<b>7Ax13036</b>	Accurate time/frequency comparison and dissemination through optical telecommunication networks	NEAT-FT	SIB02	Ing. Alexander Kuna, Ph.D. <b>Ústav fotoniky a elektroniky AV ČR, v.v.i.</b>